

<b>LIST OF ART CITED BY APPLICANT</b>  <b>(PTO-1449)</b>				ATTY. DOCKET NO. <b>YHK-0156</b>		APPLN. SERIAL NO. <b>10/565,387</b>	
				APPLICANT(S) <b>Sang-Jin YOON</b>			
				FILING DATE <b>January 23, 2006</b>		GROUP <b>2629</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
	6,034,482	03/07/2000	Kanazawa et al.				
	6,256,001	07/03/2001	Kim et al.				
	6,294,875	09/25/2001	Kurata et al.				
	6,603,447	08/05/2003	Ito et al.				
	6,803,888	10/12/2004	Nakamura et al.				
	6,288,692	09/11/2001	Kanazawa et al.				
	6,528,952	03/04/2003	Kato et al.				
	6,707,436	03/16/2004	Setoguchi et al.				
	6,862,009	03/01/2005	Park				
	6,876,343	04/05/2005	Myoung et al.				
	6,906,690	06/14/2005	Lim				
	6,628,087	09/2003	Roh et al.				
	7,218,292	05/2007	Kashio et al.				
	7,109,951	09/2006	Kim et al.				
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
	2001/0033255	10/2001	Otsuka et al.				
<b>U.S. PATENT APPLICATIONS</b>							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	JP 2001-272946	10/05/2001	Japan (English Abstract and Japanese Full Text)			X	
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>							
EXAMINER				DATE CONSIDERED			

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